

# STATUS OF MEDIPIX-3, PLANS FOR TIMEPIX-2



## Medipix 3 - reminder

- Medipix3 builds on the success of Medipix2 as a single photon counting imaging chip
- Added Features
  - Analogue charge summing to keep all charge information
  - Spectroscopic mode with 8 threshold levels
  - Continuous readout mode (no dead time)
  - Increased counter depth increasing dynamic range
  - Increased readout speed
  - Increased radiation hardness from 130nm CMOS process







- First engineering run (12 wafers of 100 chips) delivered early this year
- Wafer probing complete
- One wafer diced and bonded to PCBs
- Using the IC Tester data transfers speeds of 1.6 Gb/s were achieved
- Initial readout system working at low speed (USB from Prague)
- Electrical characterisation is almost completed
- Medipix3 readout integration in Pixelman is underway
- First bump bonded assemblies with wafers expected soon (~1 month)





#### **Electrical Characterisation Status**

- Almost everything works as designed:
  - Complex pixel functionality: Charge summing, 8 independent thresholds, programmable counter depth
  - Expected ENC and minimum threshold has been measured as expected in all the different pixel modes
- Need to confirm the electrical characterisation with Medipix3 Si assemblies
- We found 2 issues with the chip
  - Cas and FBK DACs are not able to supply the designed nominal voltage
  - Continuous Read Write is not working correctly





## The "analog switches" (problem)



Due to radiation and temperature an increase in the leakage current of NMOS transistors is observed



## **Temperature Measurements Setup**

- The Medipix3 has an on-chip temperature sensor in the chip periphery
- At CERN we have available the Climatic Chamber ESPEC EGNX12-6CWL (-70 °C to +180 °C)
- Measurements covered the -60 °C to 60 °C range







- Vcas is pulled low since the current leakage path goes to GND
- Vfbk is pulled high
- The consequence of this is effect is that the operational biasing of the front end is not stable in temperature and it must be controlled carefully





## **Temperature effects in one pixel**

- The chip is operational in all the studied temperature range
- But, we observe variations on the noise, threshold position and gain





## **Pixel to pixel gain variation**

 Gain variation (0.086 e<sup>-</sup>/THL DAC step) is due to the Medipix3 shaper stage





# **Overall pixel noise variation**

• Noise is increasing at low temperature probably due the change in front end bias voltages Vcas and Vfbk





## **Overall threshold position shift**

- Significant effect visible in the threshold position due to the variation on Vcas
- When the shaper's pol-zero cancellation circuit is activated the measured temperature sensitivity is 16.7 e<sup>-</sup>/°C and 3.7 e<sup>-</sup>/°C when it is switched off.





#### **400Mrad Irradiation**

- Used a calibrated X-ray machine (Seifert RP149)
- Beam profile is smaller than the Medipix3  $\rightarrow$  Two runs:

#### **On the Pixel Matrix 60Mrad**

**Threshold Variation** 

**Gain Variation** 

Noise Increase

#### **On the Periphery 400Mrad**

**Check DACs** 

E-fuses

Logic functionality





#### **Performance after 460MRad**

Noise Threshold σ=1.72 ke⁻ σ=12.9 e⁻ μ=9.3 ke<sup>-</sup> µ=71.6 e⁻ Counts  $^{0}\overline{0}$ 

THL [ke-] noise[e-] Threshold can be re-tuned using 5 bit equalisation

X.Llopart



#### **Performance after 460MRad**





#### **DAC Measurement**

#### NMOS DAM (Preamp)





#### **3MRad irradiation**

Worst effect at 3MRad, After this the effect of further radiation is much less.

Irradiated a small area of the chip up to 3Mrad to try and keep Cas DAC working by only damaging a limited number of pixels







#### **General behavior after 3 Mrad**

Threshold



Counts 



## **Overall threshold position variation**



point.

X.Llopart

of this diode at 3Mrad is ~5 to 10 nA.

This is the worst radiation operation



#### **3MRad Noise and Gain Result**



THL [DAC step]



# **Wafer Probing Summary**

Name	#	AA	Bs	Cs	Ds	E	F	# Chips	Where
VK7DG2H	0							100	CERN/diced
VT7DCWH	1	27	10	11	45	3	4	100	CERN
VT7DEVH	2	71	17	2	2	6	2	100	Bump bonding
VV7DFAH	3	33	18	6	32	7	4	100	CERN
VN7DE0H	4	57	18	2	15	8	0	100	Bump bonding
VU7DCVH	5	18	5	1	63	10	3	100	CERN
VW7DF9H	6	36	18	4	30	6	6	100	CERN
VQ7DCZH	7	61	18	2	8	6	5	100	Bump bonding
VS7DCXH	8	6	0	1	84	9	0	100	CERN
VU7DDCH	9	47	21	2	16	12	2	100	CERN
VL7DFJH	10	33	19	7	36	5	0	100	CERN
VW7DDAH	11	48	22	5	15	9	1	100	CERN
		437	166	43	346	81	27	1100	
		39.7%	15.1%	3.9%	31.5%	7.4%	2.5%	100.0%	



#### **Best and worst wafer**







#### Conclusions

- The electrical characterisation of the chip is basically completed
- By monitoring the chip temperature and the radiation effects through Vcas line the chip is practically insensitive to radiation large temperature fluctuations
- Only remaining issue is to understand the failure mechanism of the CRW mode
- Yield results are very encouraging given the complexity of such chip
- First Si assemblies will be available shortly and will be use to confirm electrical measurements





## **Towards Timepix2**

- In the Medipix3 collaboration there is a growing interest in Timepix2
- It might be possible to fund this development with the Medipix3 funds
- Main specs:
  - Pixel to measure TOT and Arrival time information simultaneously
  - <2ns time resolution</p>
  - Triggered readout
  - Sparse and very fast readout
- Many building blocks used in Medipix3 can be reused for a new chip
- Start of design depends on available experienced man-power